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### **Claims**

This listing of claims replaces any previous listing of claims.

### 1-39. (canceled)

- 40. (currently amended) A mold for molding a package for at least one die bonded to a substrate, the mold comprising a first mold portion that defines a package cover for encapsulating the at least one die and a portion of a surface of the substrate to which the die is bonded, and a second mold portion that defines a rib having a thickness at least as great as a solder bump thickness and that projects outwardly from a surface of the substrate opposite the surface of the substrate to which the at least one die is bonded.
- 41. (original) The mold of claim 40, wherein the first mold portion and the second mold portion define package covers and ribs for a plurality of die bonded to the substrate.
- 42. (new) The mold of claim 42, wherein the first mold portion is configured to define the package cover to encapsulate at least a portion of the surface of the substrate opposite the surface of the substrate to which the at least one die is bonded.
- 43. (new) The mold of claim 42, wherein the first mold portion is configured to contact the second mold portion.
- 44. (new) The mold of claim 42, wherein the first mold portion is configured to define the cover to encapsulate at least a portion of a substrate edge.
- 45. (new) The mold of claim 42, wherein the second mold portion is configured to encapsulate at least a portion of a substrate edge.
- 46. (new) The mold of claim 40, wherein the first mold portion is configured to contact the second mold portion.

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- 47. (new) A mold for molding a package for at least one die bonded to a substrate, the mold comprising a first mold portion that defines a package cover for encapsulating the at least one die and at least a perimeter portion of a surface to which the die is bonded, and a second mold portion that defines a rib that projects outwardly from a surface of the substrate opposite the surface of the substrate to which the at least one die is bonded.
- 48. (new) The mold of claim 47, wherein the first mold portion and the second mold portion define package covers and ribs for a plurality of die bonded to one or more substrates.
- 49. (new) The mold of claim 48, wherein the rib defined by the second mold portion has a thickness at least as great as a solder ball thickness.
- 50. (new) The mold of claim 47, wherein the package cover defined by the first mold portion is configured to encapsulate at least a portion of an edge of the substrate to which the at least one die is bonded.
- 51. (new) A mold for molding a package for a ball grid array assembly having a surface configured to receive solder bumps, comprising a first mold portion and a second mold portion that define a cavity that substantially covers the ball grid array assembly except at the surface configured to receive solder bumps.
- 52. (new) The mold of claim 51, wherein the cavity defined by the first mold portion and the second mold portion includes a rib portion configured to define at least one rib on the surface configured to receive solder bumps.
- 53. (new) The mold of claim 51, wherein the cavity defined by the first mold portion and the second mold portion includes a rib portion configured to define a plurality of ribs on the surface configured to receive solder bumps.

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- 54. (new) The mold of claim 51, wherein the cavity defined by the first mold portion and the second mold portion includes a perimeter portion associated with encapsulation of at least a portion of a perimeter of the surface configured to receive solder bumps.
- 55. (new) The mold of claim 54, wherein the perimeter portion of the cavity defines a rib that extends along a perimeter of the surface configured to receive solder bumps.

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